

<b>Notice of References Cited</b>	Application/Control No. 10/024,857	Applicant(s)/Patent Under Reexamination WALLACH ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0082000	04-2004	Stanton, Vincent P. JR.	435/006
	B	US-2004/0006553	01-2004	de Vries et al.	707/1
	C	US-2003/0208378	11-2003	Thangaraj et al.	705/2
	D	US-2003/0097220	05-2003	Agur et al.	702/19
	E	US-2003/0097077	05-2003	Morganroth, Joel	600/509
	F	US-2002/0095258	07-2002	Agur et al.	702/19
	G	US-2002/0012921	01-2002	Stanton, Vincent P. JR.	435/6
	H	US-6,317,731	11-2001	Luciano, Joanne Sylvia	706/21
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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